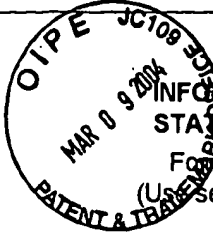
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				First Named Inventor	Jack Zezhong Peng
				Group Art Unit	2818
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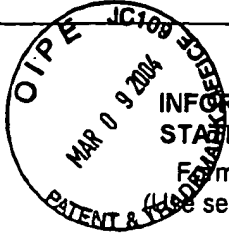
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Examiner Initials	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
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		4,322,822		McPherson	03/30/82	
		4,488,262		Basire et al.	12/11/84	
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EXAMINER <i>[Signature: Sze Suwong]</i>	DATE CONSIDERED <i>9/04</i>
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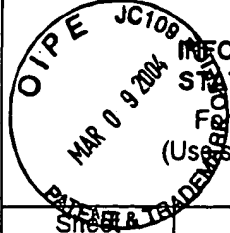
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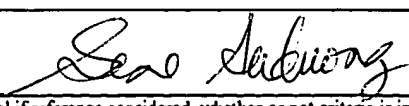
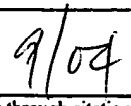
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Examiner Initials*	Cite No.	Foreign Patent or Application			Name of Patentee or Applicant of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T
		Office	NUMBER	Kind Code (if known)				
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	*	JP	61292295		Fujitsu Ltd.	12/23/86		

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P	*	MIRANDA, ENRIQUE et al; Analytic Modeling of Leakage Current Through Multiple Breakdown Paths in SiO2 Films; 39 th Annual International Reliability Physics Symposium; Orlando, FL 2001.		
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EXAMINER	<i>Sore Aubrey</i>	DATE CONSIDERED	<i>9/04</i>
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				Attorney Docket No.	38484-8005US2

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Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.	T
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